

Title (en)
METHOD FOR TESTING CIRCUITS

Title (de)
Verfahren zum Prüfen von Schaltungen

Title (fr)
PROCEDE DESTINE A TESTER DES CIRCUITS

Publication
EP 1212626 A4 20060524 (EN)

Application
EP 00939316 A 20000519

Priority

- US 0013862 W 20000519
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Abstract (en)
[origin: WO0070358A1] The present disclosure relates to a method for testing a circuit having analog components. The method comprises performing a low-cost optimized test on the circuit by applying an optimized input stimulus (20) to the circuit, capturing the circuit response (22) to the input stimulus (20) applied to the circuit, evaluating the circuit response to predict whether the performance parameters of the circuit satisfies predetermined specifications (24) for the circuit, and making a pass/fail determination (26) for the circuit based upon the evaluating of the circuit response.

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G01R 31/02

IPC 8 full level
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CPC (source: EP US)
G01R 31/01 (2013.01 - EP US); **G01R 31/2846** (2013.01 - EP); **G01R 31/3163** (2013.01 - EP)

Citation (search report)

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Designated contracting state (EPC)
DE

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